



HIGH-SPEED 3.3V 32K x 18 DUAL-PORT STATIC RAM

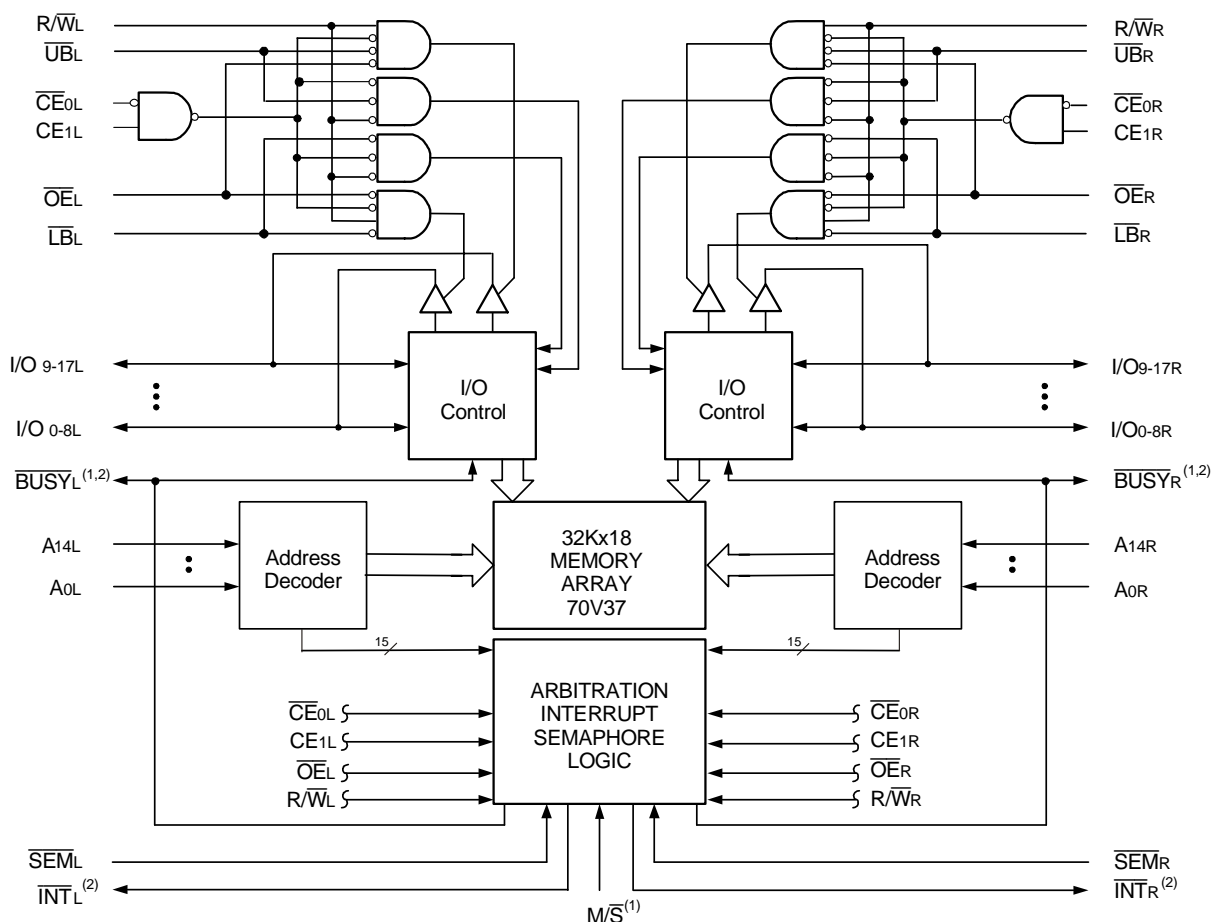
IDT70V37L

LEAD FINISH (SnPb) ARE IN EOL PROCESS - LAST TIME BUY EXPIRES JUNE 15, 2018

Features

- ♦ True Dual-Ported memory cells which allow simultaneous access of the same memory location
- ♦ High-speed access
 - Commercial: 15/20ns (max.)
 - Industrial: 20ns (max.)
- ♦ Low-power operation
 - IDT70V37L
 - Active: 440mW (typ.)
 - Standby: 660μW (typ.)
- ♦ Dual chip enables allow for depth expansion without external logic
- ♦ IDT70V37 easily expands data bus width to 36 bits or more using the Master/Slave select when cascading more than one device
- ♦ $M/\bar{S} = V_{IH}$ for \overline{BUSY} output flag on Master, $M/\bar{S} = V_{IL}$ for \overline{BUSY} input on Slave
- ♦ Busy and Interrupt Flags
- ♦ On-chip port arbitration logic
- ♦ Full on-chip hardware support of semaphore signaling between ports
- ♦ Fully asynchronous operation from either port
- ♦ Separate upper-byte and lower-byte controls for multiplexed bus and bus matching compatibility
- ♦ LVTTTL-compatible, single 3.3V ($\pm 0.3V$) power supply
- ♦ Available in a 100-pin TQFP
- ♦ Industrial temperature range ($-40^{\circ}C$ to $+85^{\circ}C$) is available for selected speeds
- ♦ Green parts available, see ordering information

Functional Block Diagram



NOTES:

- \overline{BUSY} is an input as a Slave ($M/\bar{S} = V_{IL}$) and an output when it is a Master ($M/\bar{S} = V_{IH}$).
- \overline{BUSY} and \overline{INT} are non-tri-state totem-pole outputs (push-pull).

4851 drw 01

DECEMBER 2017

Description

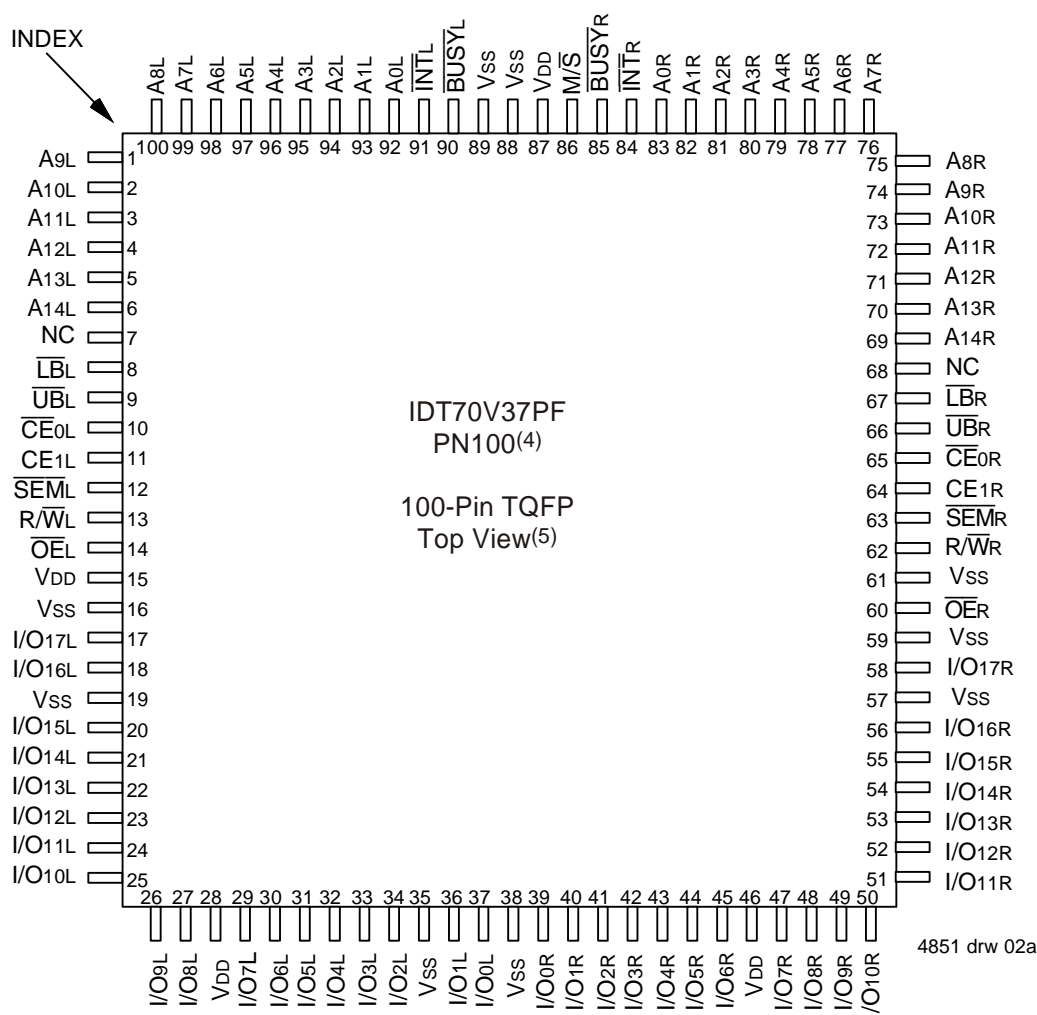
The IDT70V37 is a high-speed 32K x 18 Dual-Port Static RAM. The IDT70V37 is designed to be used as a stand-alone 576K-bit Dual-Port RAM or as a combination MASTER/SLAVE Dual-Port RAM for 36-bit or more word system. Using the IDT MASTER/SLAVE Dual-Port RAM approach in 36-bit or wider memory system applications results in full-speed, error-free operation without the need for additional discrete logic.

This device provides two independent ports with separate control, address, and I/O pins that permit independent, asynchronous access for

reads or writes to any location in memory. An automatic power down feature controlled by the chip enables (either $\overline{CE}0$ or $CE1$) permit the on-chip circuitry of each port to enter a very low standby power mode.

Fabricated using CMOS high-performance technology, these devices typically operate on only 440mW of power. The IDT70V37 is packaged in a 100-pin Thin Quad Flatpack (TQFP).

Pin Configurations^(1,2,3)



NOTES:

1. All V_{DD} pins must be connected to power supply.
2. All V_{SS} pins must be connected to ground.
3. Package body is approximately 14mm x 14mm x 1.4mm.
4. This package code is used to reference the package diagram.
5. This text does not indicate orientation of the actual part-marking.

Pin Names

| Left Port | Right Port | Names |
|----------------------------------|----------------------------------|------------------------|
| \overline{CE}_{0L} , CE_{1L} | \overline{CE}_{0R} , CE_{1R} | Chip Enables |
| R/\overline{W}_L | R/\overline{W}_R | Read/Write Enable |
| \overline{OE}_L | \overline{OE}_R | Output Enable |
| A_{0L} - A_{14L} | A_{0R} - A_{14R} | Address |
| I/O_{0L} - I/O_{17L} | I/O_{0R} - I/O_{17R} | Data Input/Output |
| \overline{SEM}_L | \overline{SEM}_R | Semaphore Enable |
| \overline{UB}_L | \overline{UB}_R | Upper Byte Select |
| \overline{LB}_L | \overline{LB}_R | Lower Byte Select |
| \overline{INT}_L | \overline{INT}_R | Interrupt Flag |
| \overline{BUSY}_L | \overline{BUSY}_R | Busy Flag |
| M/\overline{S} | | Master or Slave Select |
| V_{DD} | | Power (3.3V) |
| V_{SS} | | Ground (0V) |

4851 tbl 01

Absolute Maximum Ratings⁽¹⁾

| Symbol | Rating | Commercial & Industrial | Unit |
|------------------|--------------------------------------|-------------------------|------|
| $V_{TERM}^{(2)}$ | Terminal Voltage with Respect to GND | -0.5 to +4.6 | V |
| T_{BAS} | Temperature Under Bias | -55 to +125 | °C |
| T_{STG} | Storage Temperature | -65 to +150 | °C |
| I_{OUT} | DC Output Current | 50 | mA |

4851 tbl 02

NOTES:

- Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.
- V_{TERM} must not exceed $V_{DD} + 0.3V$ for more than 25% of the cycle time or 10ns maximum, and is limited to $\leq 20mA$ for the period of $V_{TERM} \geq V_{DD} + 0.3V$.

Maximum Operating Temperature and Supply Voltage⁽¹⁾

| Grade | Ambient Temperature ⁽¹⁾ | GND | V_{DD} |
|------------|------------------------------------|-----|-----------------|
| Commercial | 0°C to +70°C | 0V | $3.3V \pm 0.3V$ |
| Industrial | -40°C to +85°C | 0V | $3.3V \pm 0.3V$ |

4851 tbl 03

NOTE:

- This is the parameter T_A . This is the "instant on" case temperature.

Recommended DC Operating Conditions

| Symbol | Parameter | Min. | Typ. | Max. | Unit |
|----------|--------------------|---------------------|------|----------------------|------|
| V_{DD} | Supply Voltage | 3.0 | 3.3 | 3.6 | V |
| V_{SS} | Ground | 0 | 0 | 0 | V |
| V_{IH} | Input High Voltage | 2.0 | — | $V_{DD} + 0.3^{(2)}$ | V |
| V_{IL} | Input Low Voltage | -0.3 ⁽¹⁾ | — | 0.8 | V |

4851 tbl 04

NOTES:

- $V_{IL} \geq -1.5V$ for pulse width less than 10ns.
- V_{TERM} must not exceed $V_{DD} + 0.3V$.

Capacitance⁽¹⁾ ($T_A = +25^\circ C$, $f = 1.0MHz$)

| Symbol | Parameter | Conditions | Max. | Unit |
|-----------------|--------------------|----------------|------|------|
| C_{IN} | Input Capacitance | $V_{IN} = 0V$ | 9 | pF |
| $C_{OUT}^{(2)}$ | Output Capacitance | $V_{OUT} = 0V$ | 10 | pF |

4851 tbl 05

NOTES:

- This parameter is determined by device characterization but is not production tested.
- C_{OUT} also references C_{IO} .

Truth Table I – Chip Enable^(1,2)

| \overline{CE} | \overline{CE}_0 | CE_1 | Mode |
|-----------------|----------------------|----------------------|---------------------------------|
| L | V_{IL} | V_{IH} | Port Selected (TTL Active) |
| | $\leq 0.2V$ | $\geq V_{DD} - 0.2V$ | Port Selected (CMOS Active) |
| H | V_{IH} | X | Port Deselected (TTL Inactive) |
| | X | V_{IL} | Port Deselected (TTL Inactive) |
| | $\geq V_{DD} - 0.2V$ | $X^{(3)}$ | Port Deselected (CMOS Inactive) |
| | $X^{(3)}$ | $\leq 0.2V$ | Port Deselected (CMOS Inactive) |

NOTES:

1. Chip Enable references are shown above with the actual \overline{CE}_0 and CE_1 levels; \overline{CE} is a reference only.
2. 'H' = V_{IH} and 'L' = V_{IL} .
3. CMOS standby requires 'X' to be either $\leq 0.2V$ or $\geq V_{DD} - 0.2V$.

4852 tbl 06

Truth Table II – Non-Contention Read/Write Control

| Inputs ⁽¹⁾ | | | | | | Outputs | | Mode |
|-----------------------|------------------|-----------------|-----------------|-----------------|------------------|---------------------|---------------------|--------------------------|
| $\overline{CE}^{(2)}$ | R/\overline{W} | \overline{OE} | \overline{UB} | \overline{LB} | \overline{SEM} | I/O ₉₋₁₇ | I/O ₀₋₈ | |
| H | X | X | X | X | H | High-Z | High-Z | Deselected: Power-Down |
| X | X | X | H | H | H | High-Z | High-Z | Both Bytes Deselected |
| L | L | X | L | H | H | DATA _{IN} | High-Z | Write to Upper Byte Only |
| L | L | X | H | L | H | High-Z | DATA _{IN} | Write to Lower Byte Only |
| L | L | X | L | L | H | DATA _{IN} | DATA _{IN} | Write to Both Bytes |
| L | H | L | L | H | H | DATA _{OUT} | High-Z | Read Upper Byte Only |
| L | H | L | H | L | H | High-Z | DATA _{OUT} | Read Lower Byte Only |
| L | H | L | L | L | H | DATA _{OUT} | DATA _{OUT} | Read Both Bytes |
| X | X | H | X | X | X | High-Z | High-Z | Outputs Disabled |

NOTES:

1. A_{0L} — A_{14L} ≠ A_{0R} — A_{14R}
2. Refer to Truth Table I - Chip Enable.

4851 tbl 07

Truth Table III – Semaphore Read/Write Control⁽¹⁾

| Inputs ⁽¹⁾ | | | | | | Outputs | | Mode |
|-----------------------|------------------|-----------------|-----------------|-----------------|------------------|---------------------|---------------------|--|
| $\overline{CE}^{(2)}$ | R/\overline{W} | \overline{OE} | \overline{UB} | \overline{LB} | \overline{SEM} | I/O ₉₋₁₇ | I/O ₀₋₈ | |
| H | H | L | X | X | L | DATA _{OUT} | DATA _{OUT} | Read Data in Semaphore Flag |
| X | H | L | H | H | L | DATA _{OUT} | DATA _{OUT} | Read Data in Semaphore Flag |
| H | ↑ | X | X | X | L | DATA _{IN} | DATA _{IN} | Write I/O ₀ into Semaphore Flag |
| X | ↑ | X | H | H | L | DATA _{IN} | DATA _{IN} | Write I/O ₀ into Semaphore Flag |
| L | X | X | L | X | L | — | — | Not Allowed |
| L | X | X | X | L | L | — | — | Not Allowed |

NOTES:

1. There are eight semaphore flags written to I/O₀ and read from all the I/Os (I/O₀-I/O₁₇). These eight semaphore flags are addressed by A₀-A₂.
2. Refer to Truth Table I - Chip Enable.

4851 tbl 08

DC Electrical Characteristics Over the Operating Temperature and Supply Voltage Range ($V_{DD} = 3.3V \pm 0.3V$)

| Symbol | Parameter | Test Conditions | 70V37L | | Unit |
|------------|--------------------------------------|---|--------|------|---------|
| | | | Min. | Max. | |
| $ I_{II} $ | Input Leakage Current ⁽¹⁾ | $V_{DD} = 3.6V, V_{IN} = 0V \text{ to } V_{DD}$ | — | 5 | μA |
| $ I_{LO} $ | Output Leakage Current | $\overline{CE}^{(2)} = V_{IH}, V_{OUT} = 0V \text{ to } V_{DD}$ | — | 5 | μA |
| V_{OL} | Output Low Voltage | $I_{OL} = +4mA$ | — | 0.4 | V |
| V_{OH} | Output High Voltage | $I_{OH} = -4mA$ | 2.4 | — | V |

NOTES:

4851 tbl 09

1. At $V_{DD} \leq 2.0V$, input leakages are undefined.
2. Refer to Truth Table I - Chip Enable.

DC Electrical Characteristics Over the Operating Temperature and Supply Voltage Range⁽⁵⁾ ($V_{DD} = 3.3V \pm 0.3V$)

| Symbol | Parameter | Test Condition | Version | 70V37L15 Com'l Only | | 70V37L20 Com'l & Ind | | Unit |
|-----------|--|--|---------|------------------------|------|-------------------------|------|------|
| | | | | Typ. ⁽¹⁾ | Max. | Typ. ⁽¹⁾ | Max. | |
| I_{DD} | Dynamic Operating Current (Both Ports Active) | $\overline{CE} = V_{IL}$, Outputs Disabled $SEM = V_{IH}$ $f = f_{MAX}^{(2)}$ | COM'L L | 145 | 235 | 135 | 205 | mA |
| | | | IND L | — | — | 135 | 220 | |
| I_{SB1} | Standby Current (Both Ports - TTL Level Inputs) | $\overline{CE}_L = \overline{CE}_R = V_{IH}$ $SEM_R = SEM_L = V_{IH}$ $f = f_{MAX}^{(2)}$ | COM'L L | 40 | 70 | 35 | 55 | mA |
| | | | IND L | — | — | 35 | 65 | |
| I_{SB2} | Standby Current (One Port - TTL Level Inputs) | $\overline{CE}^{(4)} = V_{IL}$ and $\overline{CE}^{(4)} = V_{IH}$ Active Port Outputs Disabled, $f = f_{MAX}^{(2)}$, $SEM_R = SEM_L = V_{IH}$ | COM'L L | 100 | 155 | 90 | 140 | mA |
| | | | IND L | — | — | 90 | 150 | |
| I_{SB3} | Full Standby Current (Both Ports - All CMOS Level Inputs) | Both Ports \overline{CE}_L and $\overline{CE}_R \geq V_{DD} - 0.2V$, $V_{IN} \geq V_{DD} - 0.2V$ or $V_{IN} \leq 0.2V$, $f = 0^{(3)}$ $SEM_R = SEM_L \geq V_{DD} - 0.2V$ | COM'L L | 0.2 | 3.0 | 0.2 | 3.0 | mA |
| | | | IND L | — | — | 0.2 | 3.0 | |
| I_{SB4} | Full Standby Current (One Port - All CMOS Level Inputs) | $\overline{CE}^{(4)} \leq 0.2V$ and $\overline{CE}^{(4)} \geq V_{DD} - 0.2V$, $SEM_R = SEM_L \geq V_{DD} - 0.2V$, $V_{IN} \geq V_{DD} - 0.2V$ or $V_{IN} \leq 0.2V$, Active Port Outputs Disabled, $f = f_{MAX}^{(2)}$ | COM'L L | 95 | 150 | 90 | 135 | mA |
| | | | IND L | — | — | 90 | 145 | |

NOTES:

4851 tbl 10

1. $V_{DD} = 3.3V$, $T_A = +25^\circ C$, and are not production tested. $I_{DD} DC = 90mA$ (Typ.)
2. At $f = f_{MAX}$, address and control lines (except Output Enable) are cycling at the maximum frequency read cycle of 1/trc, and using "AC Test Conditions" of input levels of GND to 3V.
3. $f = 0$ means no address or control lines change.
4. Port "A" may be either left or right port. Port "B" is the opposite from port "A".
5. Refer to Truth Table I - Chip Enable.

AC Test Conditions

| | |
|-------------------------------|-----------------|
| Input Pulse Levels | GND to 3.0V |
| Input Rise/Fall Times | 3ns Max. |
| Input Timing Reference Levels | 1.5V |
| Output Reference Levels | 1.5V |
| Output Load | Figures 1 and 2 |

4851 tbl 11

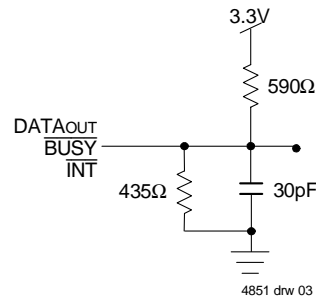


Figure 1. AC Output Load

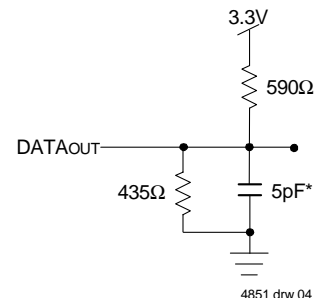
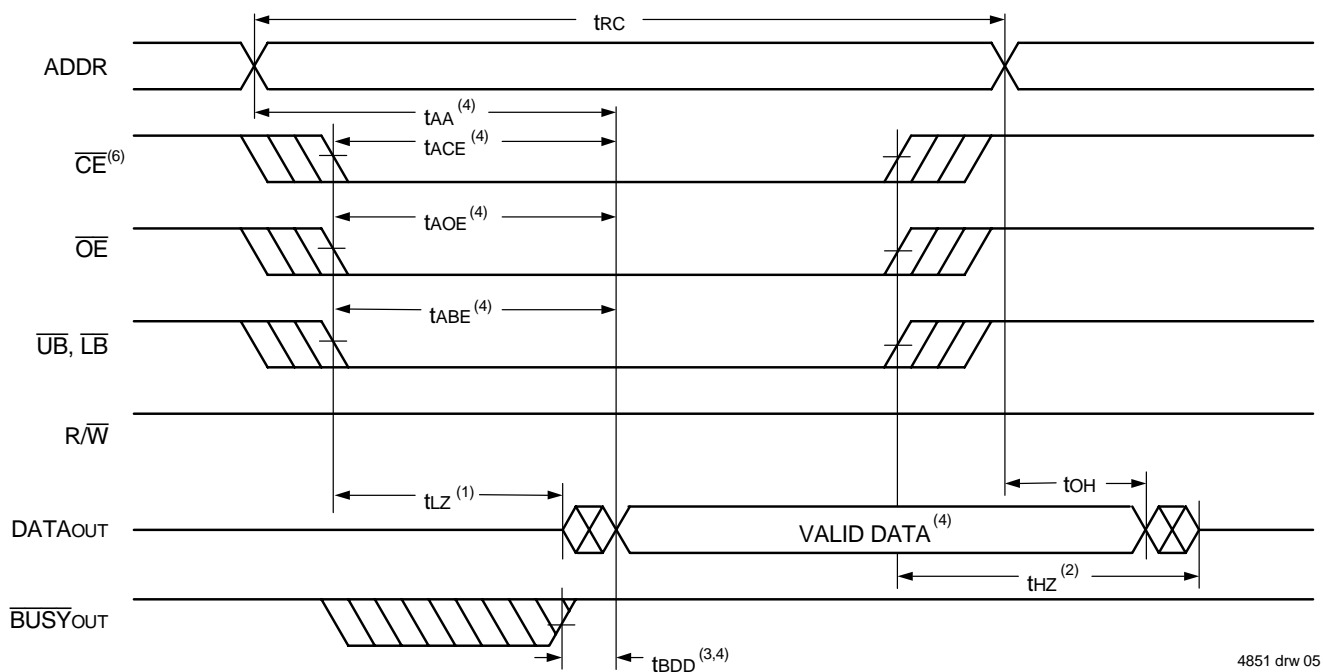


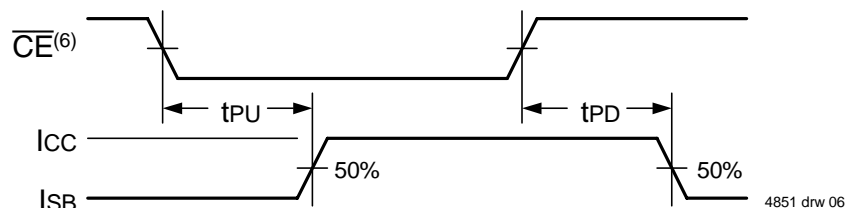
Figure 2. Output Test Load
(for tLZ, tHZ, tWZ, tOW)

* Including scope and jig.

Waveform of Read Cycles⁽⁵⁾



Timing of Power-Up Power-Down



NOTES:

- Timing depends on which signal is asserted last, \overline{OE} , \overline{CE} , \overline{LB} or \overline{UB} .
- Timing depends on which signal is de-asserted first \overline{CE} , \overline{OE} , \overline{LB} or \overline{UB} .
- tBDD delay is required only in cases where the opposite port is completing a write operation to the same address location. For simultaneous read operations \overline{BUSY} has no relation to valid output data.
- Start of valid data depends on which timing becomes effective last tAOE, tACE, tAA or tBDD.
- $\overline{SEM} = V_{IH}$.
- Refer to Truth Table I - Chip Enable.

AC Electrical Characteristics Over the Operating Temperature and Supply Voltage Range

| | | 70V37L15 Com'l Only | | 70V37L20 Com'l & Ind | | Unit |
|------------------|---|------------------------|------|-------------------------|------|------|
| Symbol | Parameter | Min. | Max. | Min. | Max. | |
| READ CYCLE | | | | | | |
| t _{RC} | Read Cycle Time | 15 | — | 20 | — | ns |
| t _{AA} | Address Access Time | — | 15 | — | 20 | ns |
| t _{ACE} | Chip Enable Access Time ⁽³⁾ | — | 15 | — | 20 | ns |
| t _{ABE} | Byte Enable Access Time ⁽³⁾ | — | 15 | — | 20 | ns |
| t _{AOE} | Output Enable Access Time | — | 10 | — | 12 | ns |
| t _{OH} | Output Hold from Address Change | 3 | — | 3 | — | ns |
| t _{LZ} | Output Low-Z Time ^(1,2) | 3 | — | 3 | — | ns |
| t _{HZ} | Output High-Z Time ^(1,2) | — | 10 | — | 10 | ns |
| t _{PU} | Chip Enable to Power Up Time ⁽²⁾ | 0 | — | 0 | — | ns |
| t _{PD} | Chip Disable to Power Down Time ⁽²⁾ | — | 15 | — | 20 | ns |
| t _{SOP} | Semaphore Flag Update Pulse (\overline{OE} or \overline{SEM}) | 10 | — | 10 | — | ns |
| t _{SAA} | Semaphore Address Access Time | — | 15 | — | 20 | ns |

4851 tbl 12

AC Electrical Characteristics Over the Operating Temperature and Supply Voltage

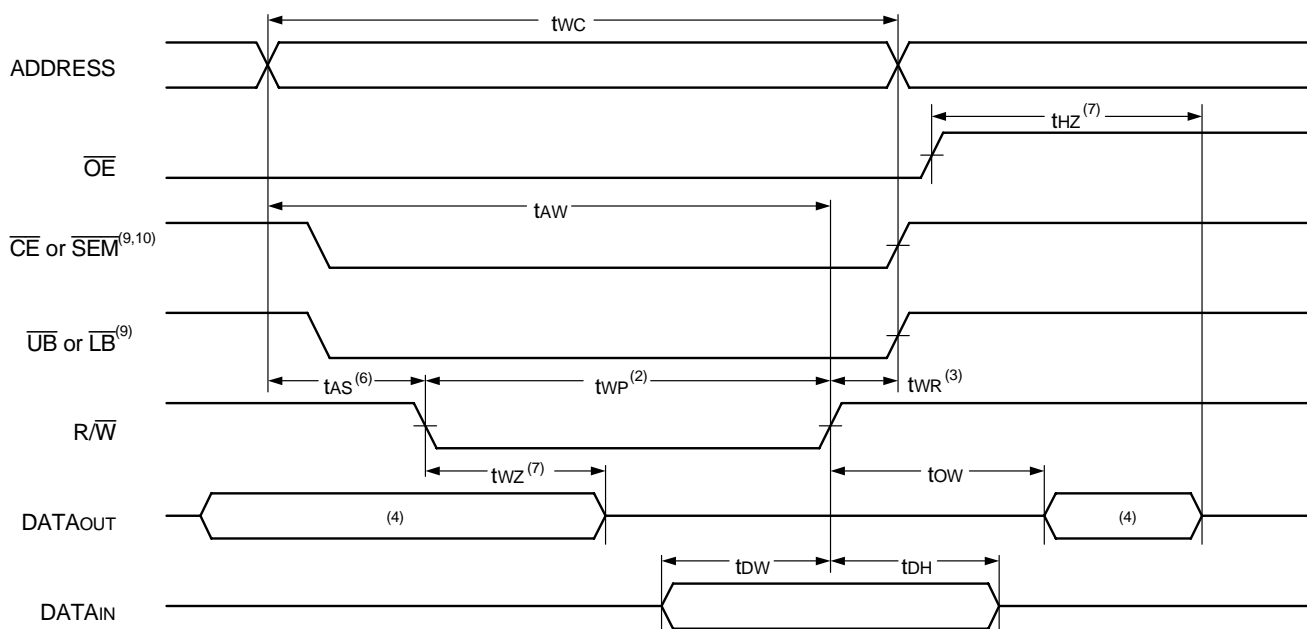
| Symbol | Parameter | 70V37L15 Com'l Only | | 70V37L20 Com'l & Ind | | Unit |
|-------------|--|------------------------|------|----------------------------|------|------|
| | | Min. | Max. | Min. | Max. | |
| WRITE CYCLE | | | | | | |
| tWC | Write Cycle Time | 15 | — | 20 | — | ns |
| tEW | Chip Enable to End-of-Write ⁽³⁾ | 12 | — | 15 | — | ns |
| tAW | Address Valid to End-of-Write | 12 | — | 15 | — | ns |
| tAS | Address Set-up Time ⁽³⁾ | 0 | — | 0 | — | ns |
| tWP | Write Pulse Width | 12 | — | 15 | — | ns |
| tWR | Write Recovery Time | 0 | — | 0 | — | ns |
| tDW | Data Valid to End-of-Write | 10 | — | 15 | — | ns |
| tHZ | Output High-Z Time ^(1,2) | — | 10 | — | 10 | ns |
| tDH | Data Hold Time ⁽⁴⁾ | 0 | — | 0 | — | ns |
| twZ | Write Enable to Output in High-Z ^(1,2) | — | 10 | — | 10 | ns |
| tOW | Output Active from End-of-Write ^(1,2,4) | 0 | — | 0 | — | ns |
| tSWRD | SEM Flag Write to Read Time | 5 | — | 5 | — | ns |
| tSPS | SEM Flag Contention Window | 5 | — | 5 | — | ns |

4851 tbl 13

NOTES:

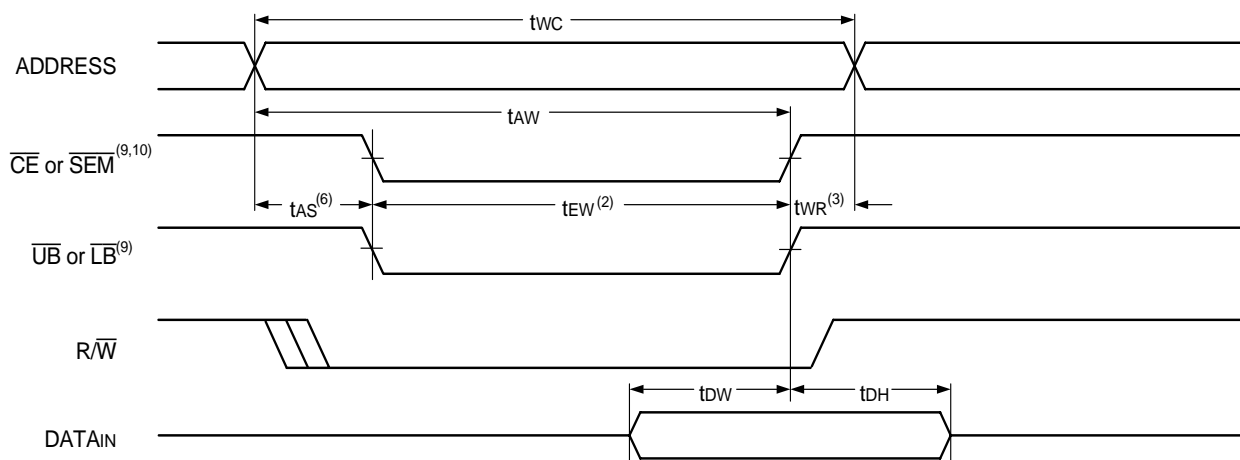
1. Transition is measured 0mV from Low or High-impedance voltage with Output Test Load (Figure 2).
2. This parameter is guaranteed by device characterization, but is not production tested.
3. To access RAM, $\overline{CE} = V_{IL}$ and $\overline{SEM} = V_{IH}$. To access semaphore, $\overline{CE} = V_{IH}$ and $\overline{SEM} = V_{IL}$. Either condition must be valid for the entire t_{EW} time.
4. The specification for t_{DH} must be met by the device supplying write data to the RAM under all operating conditions. Although t_{DH} and t_{OW} values will vary over voltage and temperature, the actual t_{DH} will always be smaller than the actual t_{OW}.

Timing Waveform of Write Cycle No. 1, R/\overline{W} Controlled Timing^(1,5,8)



4851 drw 07

Timing Waveform of Write Cycle No. 2, \overline{CE} Controlled Timing^(1,5)

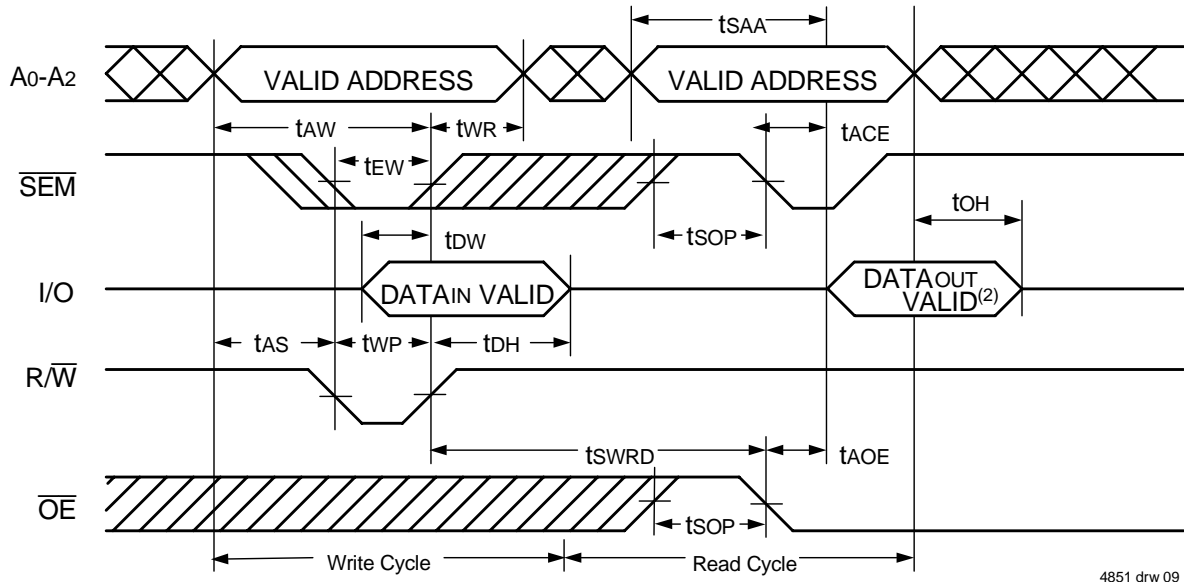


4851 drw 08

NOTES:

1. R/\overline{W} or \overline{CE} or \overline{UB} and $\overline{LB} = V_{IH}$ during all address transitions.
2. A write occurs during the overlap (t_{EW} or t_{WP}) of a $\overline{CE} = V_{IL}$ and a $R/\overline{W} = V_{IL}$ for memory array writing cycle.
3. t_{WR} is measured from the earlier of \overline{CE} or R/\overline{W} (or \overline{SEM} or R/\overline{W}) going HIGH to the end of write cycle.
4. During this period, the I/O pins are in the output state and input signals must not be applied.
5. If the \overline{CE} or $\overline{SEM} = V_{IL}$ transition occurs simultaneously with or after the $R/\overline{W} = V_{IL}$ transition, the outputs remain in the High-impedance state.
6. Timing depends on which enable signal is asserted last, \overline{CE} or R/\overline{W} .
7. This parameter is guaranteed by device characterization, but is not production tested. Transition is measured 0mV from steady state with the Output Test Load (Figure 2).
8. If $\overline{OE} = V_{IL}$ during R/\overline{W} controlled write cycle, the write pulse width must be the larger of t_{WP} or ($t_{WZ} + t_{OW}$) to allow the I/O drivers to turn off and data to be placed on the bus for the required t_{OW} . If $\overline{OE} = V_{IH}$ during an R/\overline{W} controlled write cycle, this requirement does not apply and the write pulse can be as short as the specified t_{WP} .
9. To access RAM, $\overline{CE} = V_{IL}$ and $\overline{SEM} = V_{IH}$. To access semaphore, $\overline{CE} = V_{IH}$ and $\overline{SEM} = V_{IL}$. t_{EW} must be met for either condition.
10. Refer to Truth Table I - Chip Enable.

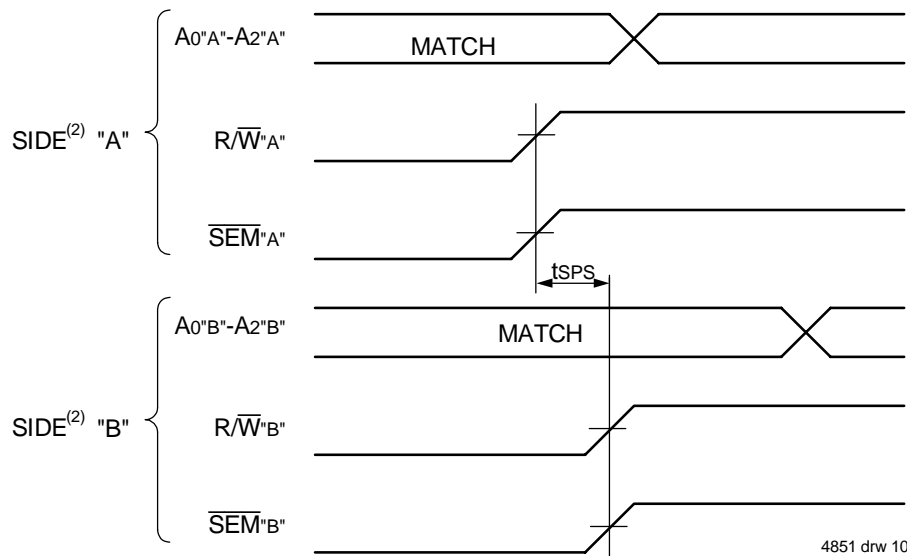
Timing Waveform of Semaphore Read after Write Timing, Either Side⁽¹⁾



NOTES:

1. $\overline{CE} = V_{IH}$ or \overline{UB} and $\overline{LB} = V_{IH}$ for the duration of the above timing (both write and read cycle) (Refer to Truth Table I - Chip Enable).
2. "DATAOUT VALID" represents all I/O's (I/O₀ - I/O₁₇) equal to the semaphore value.

Timing Waveform of Semaphore Write Contention^(1,3,4)



NOTES:

1. $D_{OR} = D_{OL} = V_{IL}$, $\overline{CE}_L = \overline{CE}_R = V_{IH}$ or both \overline{UB} and $\overline{LB} = V_{IH}$ (Refer to Truth Table I - Chip Enable).
2. All timing is the same for left and right ports. Port "A" may be either left or right port. "B" is the opposite from port "A".
3. This parameter is measured from $R/\overline{W}-A$ or $\overline{SEM}-A$ going HIGH to $R/\overline{W}-B$ or $\overline{SEM}-B$ going HIGH.
4. If t_{SPS} is not satisfied, the semaphore will fall positively to one side or the other, but there is no guarantee which side will be granted the semaphore flag.

AC Electrical Characteristics Over the Operating Temperature and Supply Voltage Range

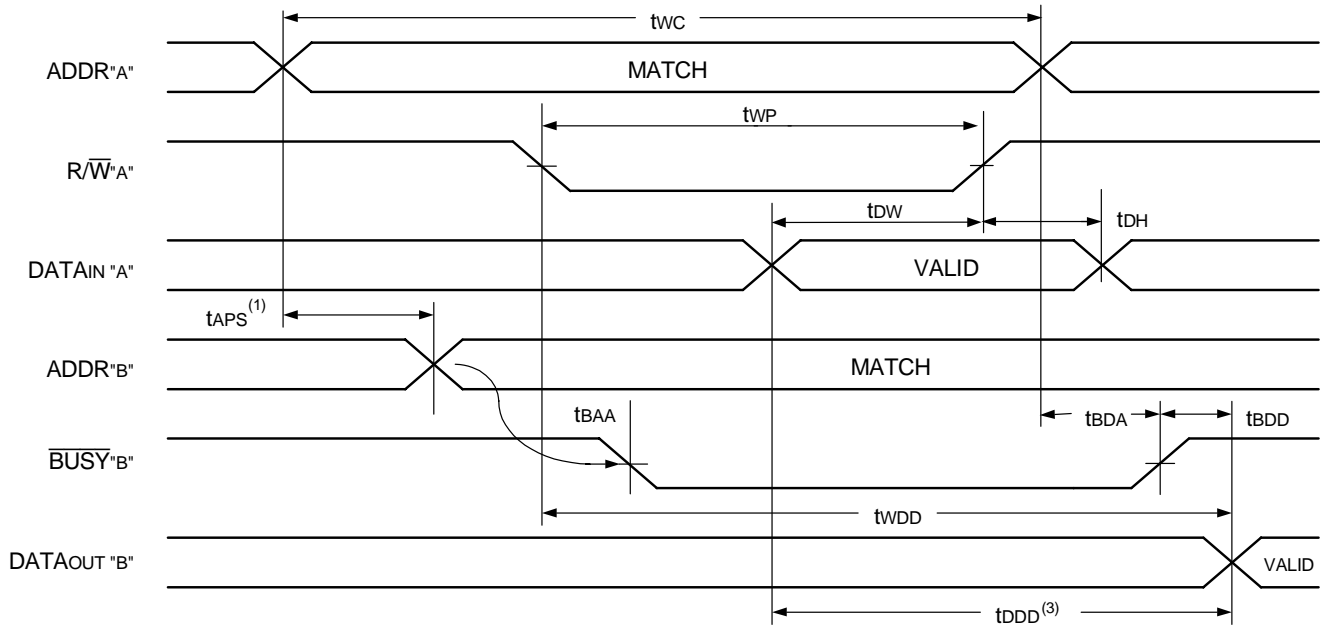
| | | 70V37L15 Com'l Only | | 70V37L20 Com'l & Ind | | |
|--|--|------------------------|------|-------------------------|------|------|
| Symbol | Parameter | Min. | Max. | Min. | Max. | Unit |
| BUSY TIMING ($M/\bar{S}=V_{IH}$) | | | | | | |
| t _{BAA} | $\bar{B}USY$ Access Time from Address Match | — | 15 | — | 20 | ns |
| t _{BDA} | $\bar{B}USY$ Disable Time from Address Not Matched | — | 15 | — | 20 | ns |
| t _{BAC} | $\bar{B}USY$ Access Time from Chip Enable Low | — | 15 | — | 20 | ns |
| t _{BDC} | $\bar{B}USY$ Access Time from Chip Enable High | — | 15 | — | 17 | ns |
| t _{APS} | Arbitration Priority Set-up Time ⁽²⁾ | 5 | — | 5 | — | ns |
| t _{BDD} | $\bar{B}USY$ Disable to Valid Data ⁽³⁾ | — | 15 | — | 17 | ns |
| t _{WH} | Write Hold After $\bar{B}USY$ ⁽⁵⁾ | 12 | — | 15 | — | ns |
| BUSY TIMING ($M/\bar{S}=V_{IL}$) | | | | | | |
| t _{WB} | $\bar{B}USY$ Input to Write ⁽⁴⁾ | 0 | — | 0 | — | ns |
| t _{WH} | Write Hold After $\bar{B}USY$ ⁽⁵⁾ | 12 | — | 15 | — | ns |
| PORT-TO-PORT DELAY TIMING | | | | | | |
| t _{WDD} | Write Pulse to Data Delay ⁽¹⁾ | — | 30 | — | 45 | ns |
| t _{DDD} | Write Data Valid to Read Data Delay ⁽¹⁾ | — | 25 | — | 30 | ns |

4851 tbl 14

NOTES:

1. Port-to-port delay through RAM cells from writing port to reading port, refer to "Timing Waveform of Write with Port-to-Port Read and $\bar{B}USY$ ($M/\bar{S} = V_{IH}$)".
2. To ensure that the earlier of the two ports wins.
3. t_{BDD} is a calculated parameter and is the greater of 0, t_{WDD} – t_{WP} (actual), or t_{DDD} – t_{OW} (actual).
4. To ensure that the write cycle is inhibited on port "B" during contention on port "A".
5. To ensure that a write cycle is completed on port "B" after contention on port "A".

Timing Waveform of Write with Port-to-Port Read and $\overline{\text{BUSY}}$ ($M/\overline{\text{S}} = V_{IH}$)^(2,4,5)

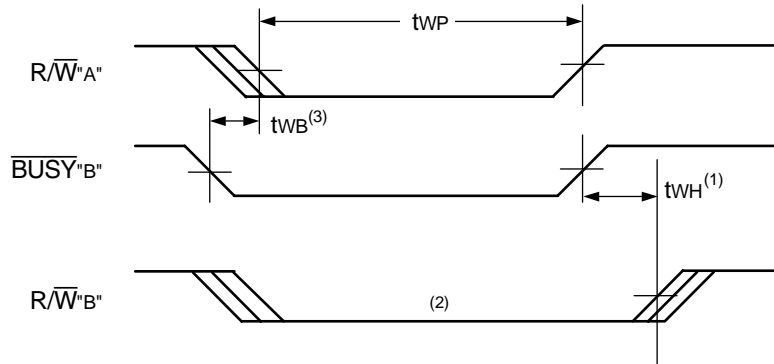


4851 drw 11

NOTES:

1. To ensure that the earlier of the two ports wins. t_{APs} is ignored for $M/\overline{\text{S}} = V_{IL}$ (SLAVE).
2. $\overline{\text{CE}}_L = \overline{\text{CE}}_R = V_{IL}$, refer to Truth Table I - Chip Enable.
3. $\overline{\text{OE}} = V_{IL}$ for the reading port.
4. If $M/\overline{\text{S}} = V_{IL}$ (slave), $\overline{\text{BUSY}}$ is an input. Then for this example $\overline{\text{BUSY}}^A = V_{IH}$ and $\overline{\text{BUSY}}^B$ input is shown above.
5. All timing is the same for left and right ports. Port "A" may be either the left or right port. Port "B" is the port opposite from port "A".

Timing Waveform of Write with $\overline{\text{BUSY}}$ ($M/\overline{\text{S}} = V_{IL}$)

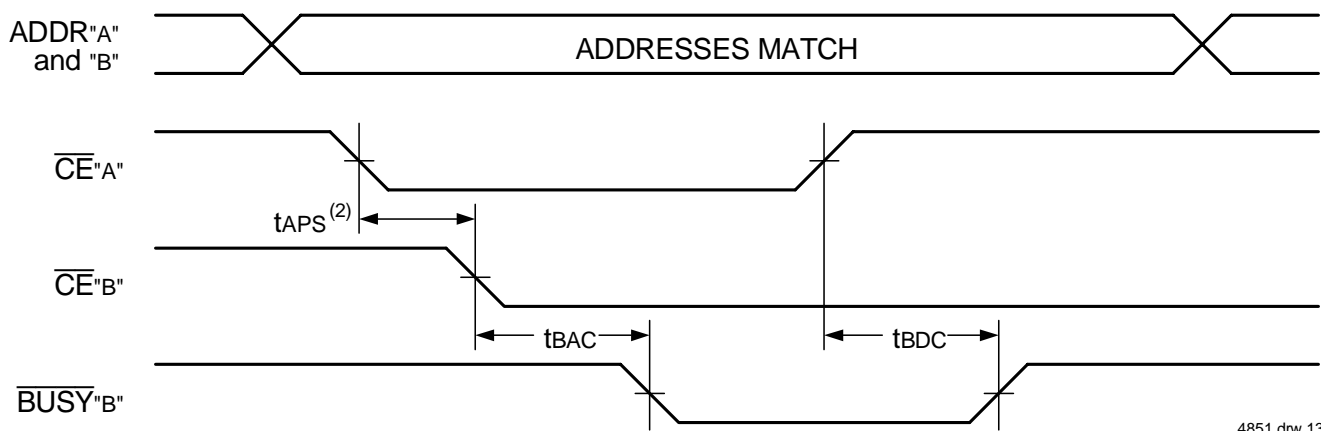


4851 drw 12

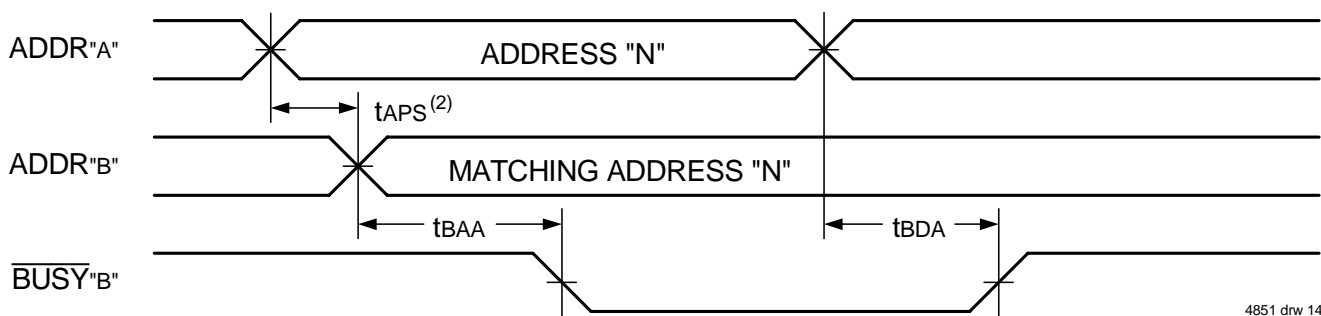
NOTES:

1. t_{WH} must be met for both $\overline{\text{BUSY}}$ input (SLAVE) and output (MASTER).
2. $\overline{\text{BUSY}}$ is asserted on port "B" blocking R/\overline{W}^B , until $\overline{\text{BUSY}}^B$ goes HIGH.
3. t_{WB} is only for the 'slave' version.

Waveform of **BUSY** Arbitration Controlled by **CE** Timing ($M/\bar{S} = V_{IH}$)^(1,3)



Waveform of **BUSY** Arbitration Cycle Controlled by Address Match Timing ($M/\bar{S} = V_{IH}$)⁽¹⁾



NOTES:

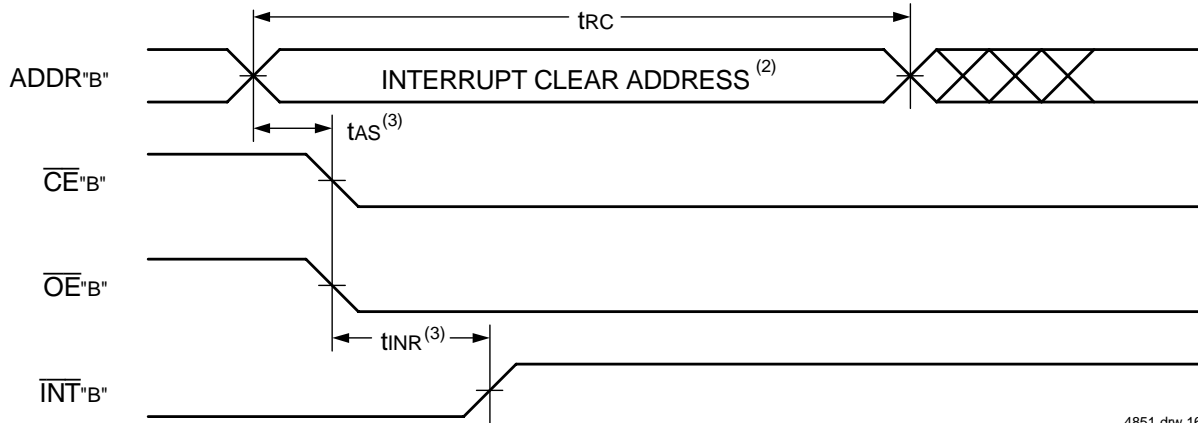
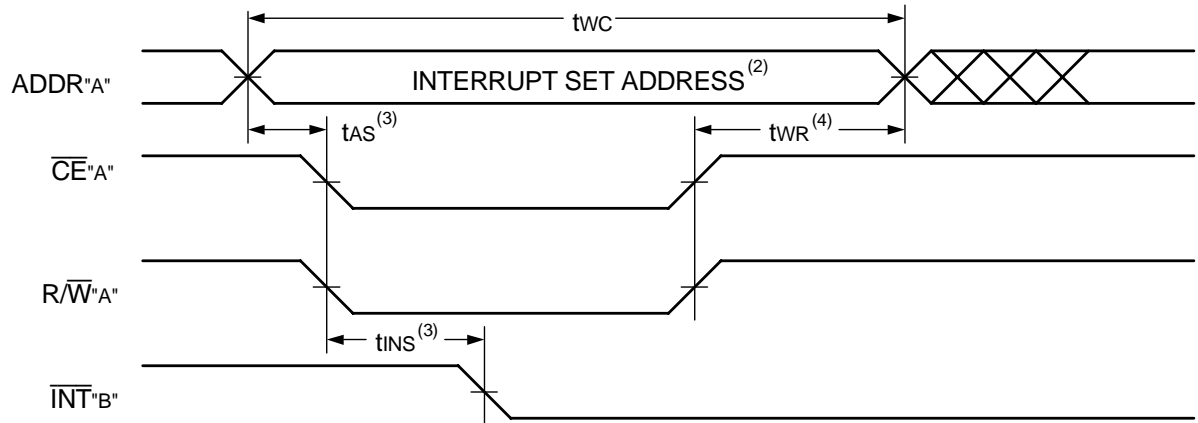
1. All timing is the same for left and right ports. Port "A" may be either the left or right port. Port "B" is the port opposite from port "A".
2. If tAPS is not satisfied, the **BUSY** signal will be asserted on one side or another but there is no guarantee on which side **BUSY** will be asserted.
3. Refer to Truth Table I - Chip Enable .

AC Electrical Characteristics Over the Operating Temperature and Supply Voltage Range

| | | 70V37L15 Com'l Only | | 70V37L20 Com'l & Ind | | |
|------------------|----------------------|------------------------|------|----------------------------|------|------|
| Symbol | Parameter | Min. | Max. | Min. | Max. | Unit |
| INTERRUPT TIMING | | | | | | |
| tAS | Address Set-up Time | 0 | — | 0 | — | ns |
| tWR | Write Recovery Time | 0 | — | 0 | — | ns |
| tINS | Interrupt Set Time | — | 15 | — | 20 | ns |
| tINR | Interrupt Reset Time | — | 15 | — | 20 | ns |

4851 tbl 15

Waveform of Interrupt Timing^(1,5)



NOTES:

1. All timing is the same for left and right ports. Port "A" may be either the left or right port. Port "B" is the port opposite from port "A".
2. Refer to Interrupt Truth Table.
3. Timing depends on which enable signal (\overline{CE} or R/\overline{W}) is asserted last.
4. Timing depends on which enable signal (\overline{CE} or R/\overline{W}) is de-asserted first.
5. Refer to Truth Table I - Chip Enable.

Truth Table IV — Interrupt Flag^(1,4,5)

| Left Port | | | | | Right Port | | | | | Function |
|------------------|-------------------|-------------------|---------------------------------|--------------------|------------------|-------------------|-------------------|---------------------------------|--------------------|-------------------------------------|
| R/W _L | \overline{CE}_L | \overline{OE}_L | A _{14L-A_{0L}} | \overline{INT}_L | R/W _R | \overline{CE}_R | \overline{OE}_R | A _{14R-A_{0R}} | \overline{INT}_R | |
| L | L | X | 7FFF | X | X | X | X | X | L ⁽²⁾ | Set Right \overline{INT}_R Flag |
| X | X | X | X | X | X | L | L | 7FFF | H ⁽³⁾ | Reset Right \overline{INT}_R Flag |
| X | X | X | X | L ⁽³⁾ | L | L | X | 7FFE | X | Set Left \overline{INT}_L Flag |
| X | L | L | 7FFE | H ⁽²⁾ | X | X | X | X | X | Reset Left \overline{INT}_L Flag |

NOTES:

1. Assumes $\overline{BUSY}_L = \overline{BUSY}_R = V_{IH}$.
2. If $\overline{BUSY}_L = V_{IL}$, then no change.
3. If $\overline{BUSY}_R = V_{IL}$, then no change.
4. \overline{INT}_L and \overline{INT}_R must be initialized at power-up.
5. Refer to Truth Table I - Chip Enable.

4851 tbl 16

Truth Table V —
Address **BUSY** Arbitration⁽⁴⁾

| Inputs | | | Outputs | | Function |
|-------------------|-------------------|--|---------------------------|---------------------------|------------------------------|
| \overline{CE}_L | \overline{CE}_R | A _{0L} -A _{14L} A _{0R} -A _{14R} | $\overline{BUSY}_L^{(1)}$ | $\overline{BUSY}_R^{(1)}$ | |
| X | X | NO MATCH | H | H | Normal |
| H | X | MATCH | H | H | Normal |
| X | H | MATCH | H | H | Normal |
| L | L | MATCH | (2) | (2) | Write Inhibit ⁽³⁾ |

NOTES:

4851 tbl 17

1. Pins \overline{BUSY}_L and \overline{BUSY}_R are both outputs when the part is configured as a master. Both are inputs when configured as a slave. \overline{BUSY} outputs on the IDT70V37 are push-pull, not open drain outputs. On slaves the \overline{BUSY} input internally inhibits writes.
2. "L" if the inputs to the opposite port were stable prior to the address and enable inputs of this port. "H" if the inputs to the opposite port became stable after the address and enable inputs of this port. If taps is not met, either \overline{BUSY}_L or \overline{BUSY}_R = LOW will result. \overline{BUSY}_L and \overline{BUSY}_R outputs can not be LOW simultaneously.
3. Writes to the left port are internally ignored when \overline{BUSY}_L outputs are driving LOW regardless of actual logic level on the pin. Writes to the right port are internally ignored when \overline{BUSY}_R outputs are driving LOW regardless of actual logic level on the pin.
4. Refer to Truth Table I - Chip Enable.

Truth Table VI — Example of Semaphore Procurement Sequence^(1,2,3)

| Functions | D ₀ - D ₁₇ Left | D ₀ - D ₁₇ Right | Status |
|------------------------------------|---------------------------------------|--|--|
| No Action | 1 | 1 | Semaphore free |
| Left Port Writes "0" to Semaphore | 0 | 1 | Left port has semaphore token |
| Right Port Writes "0" to Semaphore | 0 | 1 | No change. Right side has no write access to semaphore |
| Left Port Writes "1" to Semaphore | 1 | 0 | Right port obtains semaphore token |
| Left Port Writes "0" to Semaphore | 1 | 0 | No change. Left port has no write access to semaphore |
| Right Port Writes "1" to Semaphore | 0 | 1 | Left port obtains semaphore token |
| Left Port Writes "1" to Semaphore | 1 | 1 | Semaphore free |
| Right Port Writes "0" to Semaphore | 1 | 0 | Right port has semaphore token |
| Right Port Writes "1" to Semaphore | 1 | 1 | Semaphore free |
| Left Port Writes "0" to Semaphore | 0 | 1 | Left port has semaphore token |
| Left Port Writes "1" to Semaphore | 1 | 1 | Semaphore free |

4851 tbl 18

NOTES:

1. This table denotes a sequence of events for only one of the eight semaphores on the IDT70V37.
2. There are eight semaphore flags written to via I/O₀ and read from all I/O's (I/O₀-I/O₁₇). These eight semaphores are addressed by A₀ - A₂.
3. $\overline{CE} = V_{IH}$, $\overline{SEM} = V_{IL}$ to access the semaphores. Refer to the Truth Table III - Semaphore Read/Write Control.

Functional Description

The IDT70V37 provides two ports with separate control, address and I/O pins that permit independent access for reads or writes to any location in memory. The IDT70V37 has an automatic power down feature controlled by \overline{CE} . The \overline{CE}_0 and \overline{CE}_1 control the on-chip power down circuitry that permits the respective port to go into a standby mode when not selected ($\overline{CE} = \text{HIGH}$). When a port is enabled, access to the entire memory array is permitted.

Interrupts

If the user chooses the interrupt function, a memory location (mail box or message center) is assigned to each port. The left port interrupt flag (\overline{INT}_L) is asserted when the right port writes to memory location 7FFE

(HEX), where a write is defined as $\overline{CE}_R = R/\overline{W}_R = V_{IL}$ per the Truth Table. The left port clears the interrupt through access of address location 7FFE when $\overline{CE}_L = \overline{OE}_L = V_{IL}$, R/\overline{W} is a "don't care". Likewise, the right port interrupt flag (\overline{INT}_R) is asserted when the left port writes to memory location 7FFF (HEX) and to clear the interrupt flag (\overline{INT}_R), the right port must read the memory location 7FFF. The message (18 bits) at 7FFE or 7FFF is user-defined since it is an addressable SRAM location. If the interrupt function is not used, address locations 7FFE and 7FFF are not used as mail boxes, but as part of the random access memory. Refer to Truth Table IV for the interrupt operation.

Busy Logic

Busy Logic provides a hardware indication that both ports of the RAM have accessed the same location at the same time. It also allows one of the two accesses to proceed and signals the other side that the RAM is "Busy". The $\overline{\text{BUSY}}$ pin can then be used to stall the access until the operation on the other side is completed. If a write operation has been attempted from the side that receives a $\overline{\text{BUSY}}$ indication, the write signal is gated internally to prevent the write from proceeding.

The use of $\overline{\text{BUSY}}$ logic is not required or desirable for all applications. In some cases it may be useful to logically OR the $\overline{\text{BUSY}}$ outputs together and use any $\overline{\text{BUSY}}$ indication as an interrupt source to flag the event of an illegal or illogical operation. If the write inhibit function of $\overline{\text{BUSY}}$ logic is not desirable, the $\overline{\text{BUSY}}$ logic can be disabled by placing the part in slave mode with the $\overline{\text{M/S}}$ pin. Once in slave mode the $\overline{\text{BUSY}}$ pin operates solely as a write inhibit input pin. Normal operation can be programmed by tying the $\overline{\text{BUSY}}$ pins HIGH. If desired, unintended write operations can be prevented to a port by tying the $\overline{\text{BUSY}}$ pin for that port LOW.

The $\overline{\text{BUSY}}$ outputs on the IDT 70V37 RAM in master mode, are push-pull type outputs and do not require pull up resistors to operate. If these RAMs are being expanded in depth, then the $\overline{\text{BUSY}}$ indication for the resulting array requires the use of an external AND gate.

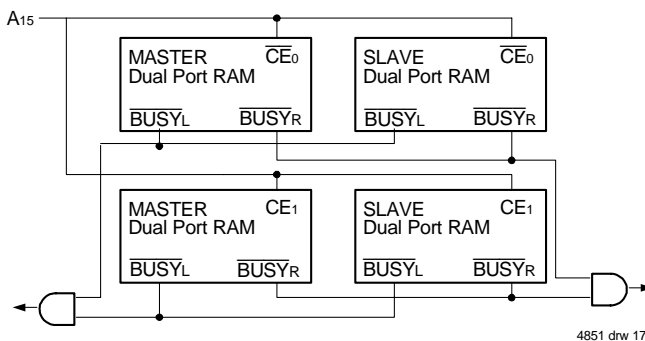


Figure 3. Busy and chip enable routing for both width and depth expansion with IDT70V37 RAMs.

Width Expansion with Busy Logic Master/Slave Arrays

When expanding an IDT70V37 RAM array in width while using $\overline{\text{BUSY}}$ logic, one master part is used to decide which side of the RAMs array will receive a $\overline{\text{BUSY}}$ indication, and to output that indication. Any number of slaves to be addressed in the same address range as the master use the $\overline{\text{BUSY}}$ signal as a write inhibit signal. Thus on the IDT70V37 RAM the $\overline{\text{BUSY}}$ pin is an output if the part is used as a master ($\overline{\text{M/S}}$ pin = V_{IH}), and the $\overline{\text{BUSY}}$ pin is an input if the part is used as a slave ($\overline{\text{M/S}}$ pin = V_{IL}) as shown in Figure 3.

If two or more master parts were used when expanding in width, a split decision could result with one master indicating $\overline{\text{BUSY}}$ on one side of the array and another master indicating $\overline{\text{BUSY}}$ on one other side of the array. This would inhibit the write operations from one port for part of a word and inhibit the write operations from the other port for the other part of the word.

The $\overline{\text{BUSY}}$ arbitration on a master is based on the chip enable and address signals only. It ignores whether an access is a read or write. In a master/slave array, both address and chip enable must be valid long

enough for a $\overline{\text{BUSY}}$ flag to be output from the master before the actual write pulse can be initiated with the $\overline{\text{R/W}}$ signal. Failure to observe this timing can result in a glitched internal write inhibit signal and corrupted data in the slave.

Semaphores

The IDT70V37 is an extremely fast Dual-Port 32K x 18 CMOS Static RAM with an additional 8 address locations dedicated to binary semaphore flags. These flags allow either processor on the left or right side of the Dual-Port RAM to claim a privilege over the other processor for functions defined by the system designer's software. As an example, the semaphore can be used by one processor to inhibit the other from accessing a portion of the Dual-Port RAM or any other shared resource.

The Dual-Port RAM features a fast access time, with both ports being completely independent of each other. This means that the activity on the left port in no way slows the access time of the right port. Both ports are identical in function to standard CMOS Static RAM and can be read from or written to at the same time with the only possible conflict arising from the simultaneous writing of, or a simultaneous READ/WRITE of, a non-semaphore location. Semaphores are protected against such ambiguous situations and may be used by the system program to avoid any conflicts in the non-semaphore portion of the Dual-Port RAM. These devices have an automatic power-down feature controlled by $\overline{\text{CE}}$, the Dual-Port RAM enable, and $\overline{\text{SEM}}$, the semaphore enable. The $\overline{\text{CE}}$ and $\overline{\text{SEM}}$ pins control on-chip power down circuitry that permits the respective port to go into standby mode when not selected. This is the condition which is shown in Truth Table III where $\overline{\text{CE}}$ and $\overline{\text{SEM}}$ are both HIGH.

Systems which can best use the IDT70V37 contain multiple processors or controllers and are typically very high-speed systems which are software controlled or software intensive. These systems can benefit from a performance increase offered by the IDT70V37's hardware semaphores, which provide a lockout mechanism without requiring complex programming.

Software handshaking between processors offers the maximum in system flexibility by permitting shared resources to be allocated in varying configurations. The IDT70V37 does not use its semaphore flags to control any resources through hardware, thus allowing the system designer total flexibility in system architecture.

An advantage of using semaphores rather than the more common methods of hardware arbitration is that wait states are never incurred in either processor. This can prove to be a major advantage in very high-speed systems.

How the Semaphore Flags Work

The semaphore logic is a set of eight latches which are independent of the Dual-Port RAM. These latches can be used to pass a flag, or token, from one port to the other to indicate that a shared resource is in use. The semaphores provide a hardware assist for a use assignment method called "Token Passing Allocation." In this method, the state of a semaphore latch is used as a token indicating that a shared resource is in use. If the left processor wants to use this resource, it requests the token by setting the latch. This processor then verifies its success in setting the latch by reading it. If it was successful, it proceeds to assume control over the shared resource. If it was not successful in setting the latch, it determines that the right side processor has set the latch first, has the token and is using the

shared resource. The left processor can then either repeatedly request that semaphore's status or remove its request for that semaphore to perform another task and occasionally attempt again to gain control of the token via the set and test sequence. Once the right side has relinquished the token, the left side should succeed in gaining control.

The semaphore flags are active LOW. A token is requested by writing a zero into a semaphore latch and is released when the same side writes a one to that latch.

The eight semaphore flags reside within the IDT70V37 in a separate memory space from the Dual-Port RAM. This address space is accessed by placing a low input on the **SEM** pin (which acts as a chip select for the semaphore flags) and using the other control pins (Address, **CE**, and **R/W**) as they would be used in accessing a standard Static RAM. Each of the flags has a unique address which can be accessed by either side through address pins A0 – A2. When accessing the semaphores, none of the other address pins has any effect.

When writing to a semaphore, only data pin D0 is used. If a low level is written into an unused semaphore location, that flag will be set to a zero on that side and a one on the other side (see Truth Table VI). That semaphore can now only be modified by the side showing the zero. When a one is written into the same location from the same side, the flag will be set to a one for both sides (unless a semaphore request from the other side is pending) and then can be written to by both sides. The fact that the side which is able to write a zero into a semaphore subsequently locks out writes from the other side is what makes semaphore flags useful in interprocessor communications. (A thorough discussion on the use of this feature follows shortly.) A zero written into the same location from the other side will be stored in the semaphore request latch for that side until the semaphore is freed by the first side.

When a semaphore flag is read, its value is spread into all data bits so that a flag that is a one reads as a one in all data bits and a flag containing a zero reads as all zeros. The read value is latched into one side's output register when that side's semaphore select (**SEM**) and output enable (**OE**) signals go active. This serves to disallow the semaphore from changing state in the middle of a read cycle due to a write cycle from the other side. Because of this latch, a repeated read of a semaphore in a test loop must cause either signal (**SEM** or **OE**) to go inactive or the output will never change.

A sequence WRITE/READ must be used by the semaphore in order to guarantee that no system level contention will occur. A processor requests access to shared resources by attempting to write a zero into a semaphore location. If the semaphore is already in use, the semaphore request latch will contain a zero, yet the semaphore flag will appear as one, a fact which the processor will verify by the subsequent read (see Table VI). As an example, assume a processor writes a zero to the left port at a free semaphore location. On a subsequent read, the processor will verify that it has written successfully to that location and will assume control over the resource in question. Meanwhile, if a processor on the right side attempts to write a zero to the same semaphore flag it will fail, as will be verified by the fact that a one will be read from that semaphore on the right side during subsequent read. Had a sequence of READ/WRITE been used instead, system contention problems could have occurred during the gap between the read and write cycles.

It is important to note that a failed semaphore request must be followed by either repeated reads or by writing a one into the same location. The reason for this is easily understood by looking at the simple logic diagram

of the semaphore flag in Figure 4. Two semaphore request latches feed into a semaphore flag. Whichever latch is first to present a zero to the semaphore flag will force its side of the semaphore flag LOW and the other side HIGH. This condition will continue until a one is written to the same semaphore request latch. Should the other side's semaphore request latch have been written to a zero in the meantime, the semaphore flag will flip over to the other side as soon as a one is written into the first side's request latch. The second side's flag will now stay LOW until its semaphore request latch is written to a one. From this it is easy to understand that, if a semaphore is requested and the processor which requested it no longer needs the resource, the entire system can hang up until a one is written into that semaphore request latch.

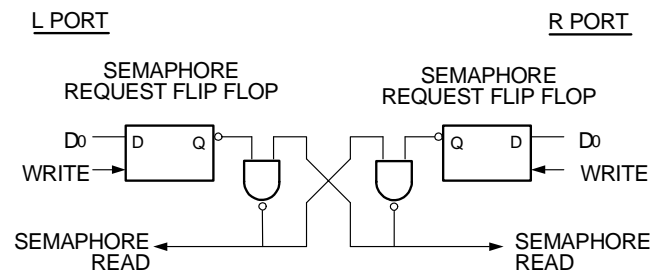


Figure 4. IDT70V37 Semaphore Logic

4851 drw 18

The critical case of semaphore timing is when both sides request a single token by attempting to write a zero into it at the same time. The semaphore logic is specially designed to resolve this problem. If simultaneous requests are made, the logic guarantees that only one side receives the token. If one side is earlier than the other in making the request, the first side to make the request will receive the token. If both requests arrive at the same time, the assignment will be arbitrarily made to one port or the other.

One caution that should be noted when using semaphores is that semaphores alone do not guarantee that access to a resource is secure. As with any powerful programming technique, if semaphores are misused or misinterpreted, a software error can easily happen.

Initialization of the semaphores is not automatic and must be handled via the initialization program at power-up. Since any semaphore request flag which contains a zero must be reset to a one, all semaphores on both sides should have a one written into them at initialization from both sides to assure that they will be free when needed.

Ordering Information

| XXXXX | A | 999 | A | A | A | A | | |
|-------------|-------|-------|---------|---|----------------------------------|---|---------------------------|---|
| Device Type | Power | Speed | Package | | Process/ Temperature Range | | | |
| | | | | | | | Blank 8 | Tube or Tray Tape and Reel |
| | | | | | | | Blank I ⁽¹⁾ | Commercial (0°C to +70°C) Industrial (-40°C to +85°C) |
| | | | | | | | G ⁽²⁾ | Green |
| | | | | | | | PF | 100-pin TQFP (PN100) |
| | | | | | | | 15 20 | Commercial Only Commercial & Industrial } Speed in nanoseconds |
| | | | | | | | L | Low Power |
| | | | | | | | 70V37 | 576K (32K x 18) Dual-Port RAM |

4851 drw 19

NOTES:

1. Contact your sales office for Industrial Temperature range in other speeds, packages and powers.
2. Green parts available. For specific speeds, packages and powers contact your sales office

LEAD FINISH (SnPb) parts are in EOL process. Product Discontinuation Notice - PDN# SP-17-02

Datasheet Document History:

| | |
|-----------|--|
| 08/01/99: | Initial Public Offering |
| 01/02/02: | Page 1 & 17 Replaced IDT logo |
| | Page 3 Increased storage temperature parameter Clarified TA Parameter |
| | Page 5 DC Electrical parameters—changed wording from "open" to "disabled" Added Truth Table I - Chip Enable as note 5 Corrected ±200mV to 0mV in notes |
| 06/17/04: | Page 5, 7, 10 & 12 Added Industrial Temperature range for 20ns to DC & AC Electrical Characteristics Removed Preliminary status |
| | Page 1 & 17 Replaced old ® logo with new ™ logo |
| | Page 2 Added date revision to pin configuration |
| | Page 2 - 5 Changed naming conventions from V _{CC} to V _{DD} and from GND to V _{SS} |
| 08/15/08: | Page 1 Added green availability to features |
| | Page 17 Added green indicator to ordering information |
| | Page 1 & 17 Updated old ™ logo with new ® logo |
| 01/19/09: | Page 17 Removed "IDT" from orderable part number |
| 06/18/15: | Page 2 Removed IDT in reference to fabrication |
| | Page 2 Removed date from the 100-pin TQFP configuration |
| | Page 2 & 17 The package code PN100-1 changed to PN100 to match standard package codes |
| | Page 17 Added Tape & Reel indicator to the Ordering Information |
| 12/14/17: | Product Discontinuation Notice - PDN# SP-17-02 Last time buy expires June 15, 2018 |



CORPORATE HEADQUARTERS
 6024 Silver Creek Valley Road
 San Jose, CA 95138

for SALES:
 800-345-7015 or 408-284-8200
 fax: 408-284-2775
 www.idt.com

for Tech Support:
 408-284-2794
 DualPortHelp@idt.com

The IDT logo is a registered trademark of Integrated Device Technology, Inc.

Mouser Electronics

Authorized Distributor

Click to View Pricing, Inventory, Delivery & Lifecycle Information:

[IDT \(Integrated Device Technology\):](#)

[70V37L20PFI8](#) [70V37L15PF](#) [70V37L20PFGI](#) [70V37L15PFG8](#) [70V37L20PFI](#) [70V37L20PF8](#) [70V37L15PFG](#)
[70V37L20PF](#) [70V37L20PFGI8](#) [70V37L15PF8](#)



Компания «ЭлектроПласт» предлагает заключение долгосрочных отношений при поставках импортных электронных компонентов на взаимовыгодных условиях!

Наши преимущества:

- Оперативные поставки широкого спектра электронных компонентов отечественного и импортного производства напрямую от производителей и с крупнейших мировых складов;
- Поставка более 17-ти миллионов наименований электронных компонентов;
- Поставка сложных, дефицитных, либо снятых с производства позиций;
- Оперативные сроки поставки под заказ (от 5 рабочих дней);
- Экспресс доставка в любую точку России;
- Техническая поддержка проекта, помощь в подборе аналогов, поставка прототипов;
- Система менеджмента качества сертифицирована по Международному стандарту ISO 9001;
- Лицензия ФСБ на осуществление работ с использованием сведений, составляющих государственную тайну;
- Поставка специализированных компонентов (Xilinx, Altera, Analog Devices, Intersil, Interpoint, Microsemi, Aeroflex, Peregrine, Syfer, Eurofarad, Texas Instrument, Miteq, Cobham, E2V, MA-COM, Hittite, Mini-Circuits, General Dynamics и др.);

Помимо этого, одним из направлений компании «ЭлектроПласт» является направление «Источники питания». Мы предлагаем Вам помощь Конструкторского отдела:

- Подбор оптимального решения, техническое обоснование при выборе компонента;
- Подбор аналогов;
- Консультации по применению компонента;
- Поставка образцов и прототипов;
- Техническая поддержка проекта;
- Защита от снятия компонента с производства.



Как с нами связаться

Телефон: 8 (812) 309 58 32 (многоканальный)

Факс: 8 (812) 320-02-42

Электронная почта: org@eplast1.ru

Адрес: 198099, г. Санкт-Петербург, ул. Калинина, дом 2, корпус 4, литера А.